

Notice of References Cited	Application/Control No. 09/558,130		Applicant(s)/Patent Under Reexamination REYNICK, JOSEPH A.	
	Examiner Russell M Kobert		Art Unit 2829	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-6,140,832	10-2000	Vu et al.	324/765
	C	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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NON-PATENT DOCUMENTS

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	V	Thibeault et al, "Diagnosis method based on Delta-Iddq probabilistic signatures: Experimental results," IEEE International Test Conference, 1998 (Month Unavailable), pp. 1019-1026.
	W	Thibeault, "On the Comparison of Delta-IDDQ and IDDQ Testing," VLSI Test Symposium, 17th IEEE Proceedings, 25-29 April 1999, pp. 143-150.
	X	Thibeault, "Improving Delta-IDDQ-based test methods," IEEE International Test Conference Proceedings, 3-5 Oct. 2000, pp. 207-206.

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.